

Search Notes

Application/Control No.

10/537,306

Examiner

Shin-Hon Chen

Applicant(s)/Patent under
Reexamination

BRIQUE ET AL.

Art Unit

2131

SEARCHED

Class	Subclass	Date	Examiner
380	231, 239	7/5/2007	S.C.
713	193	7/5/2007	S.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	7/5/2007	S.C.